National Semiconductor

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74ACQ657 • 54ACTQ/74ACTQ657 Quiet Series Octal Bidirectional Transceiver with 8-Bit Parity Generator/Checker and TRI-STATE® Outputs

General Description

The 'ACQ/'ACTQ657 contains eight non-inverting buffers with TRI-STATE outputs and an 8-bit parity generator/checker. Intended for bus oriented applications, the device combines the '245 and the '280 functions in one package.

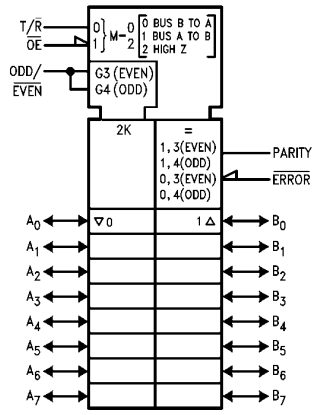
The 'ACQ/'ACTQ utilizes NSC Quiet Series technology to guarantee quiet output switching and improved dynamic threshold performance. FACT Quiet Series™ features GTO™ output control and undershoot corrector in addition to a split ground bus for superior performance.

Features

- Guaranteed simultaneous switching noise level and dynamic threshold performance
- Guaranteed pin-to-pin skew AC performance
- Combines the '245 and the '280 functions in one package
- 300 mil 24-pin slim dual-in-line package
- Outputs source/sink 24 mA
- 'ACTQ has TTL-compatible inputs
- Standard Military Drawing (SMD)
  — 'ACTQ657: 5962-92197

Logic Symbols

IEEE/IEC



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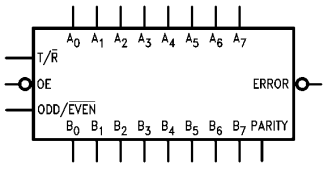

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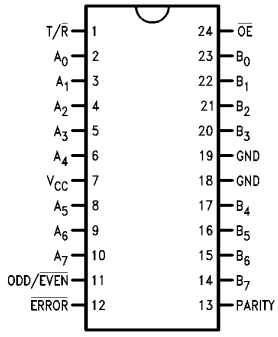
Connection Diagrams

Pin Assignment for DIP, SOIC and Flatpak



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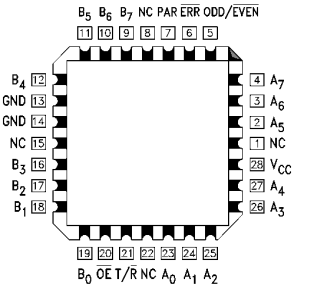
Pin Assignment for LCC



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Pin Names	Description
A_0–A_7	Data Inputs/TRI-STATE Outputs
B_0–B_7	Data Inputs/TRI-STATE Outputs
T/$\overline{R}$	Transmit/Receive Input
$\overline{OE}$	Enable Input
PARITY	Parity Input/TRI-STATE Output
ODD/$\overline{EVEN}$	ODD/$\overline{EVEN}$ Parity Input
$\overline{ERROR}$	Error TRI-STATE Output

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74ACQ657 • 54ACTQ/74ACTQ657 Quiet Series Octal Bidirectional Transceiver with 8-Bit Parity Generator/Checker and TRI-STATE Outputs

Functional Description

The Transmit/Receive ($T/\overline{R}$) input determines the direction of the data flow through the bidirectional transceivers. Transmit (active HIGH) enables data from the A port to the B port; Receive (active LOW) enables data from the B port to the A port.

The Output Enable ($\overline{OE}$) input disables the parity and $\overline{ERROR}$ outputs and both the A and B ports by placing them in a HIGH-Z condition when the Output Enable input is HIGH.

When transmitting ($T/\overline{R}$ HIGH), the parity generator detects whether an even or odd number of bits on the A port are HIGH and compares these with the condition of the parity select (ODD/$\overline{EVEN}$). If the Parity Select is HIGH and an even number of A inputs are HIGH, the Parity output is HIGH.

In receiving mode ($T/\overline{R}$ LOW), the parity select and number of HIGH inputs on port B are compared to the condition of the Parity input. If an even number of bits on the B port are HIGH, the parity select is HIGH, and the PARITY input is HIGH, then $\overline{ERROR}$ will be HIGH to indicate no error. If an odd number of bits on the B port are HIGH, the parity select is HIGH, and the PARITY input is HIGH, the $\overline{ERROR}$ will be LOW indicating an error.

Function Table

Number of Inputs That Are High	Inputs			Input/ Output	Outputs	
	$\overline{OE}$	$T/\overline{R}$	ODD/$\overline{EVEN}$	Parity	$\overline{ERROR}$	Outputs Mode
0, 2, 4, 6, 8	L	H	H	H	Z	Transmit
	L	H	L	L	Z	Transmit
	L	L	H	H	H	Receive
	L	L	H	L	L	Receive
	L	L	L	H	L	Receive
	L	L	L	L	H	Receive
1, 3, 5, 7	L	H	H	L	Z	Transmit
	L	H	L	H	Z	Transmit
	L	L	H	H	L	Receive
	L	L	H	L	H	Receive
	L	L	L	H	H	Receive
	L	L	L	L	L	Receive
Immaterial	H	X	X	Z	Z	Z

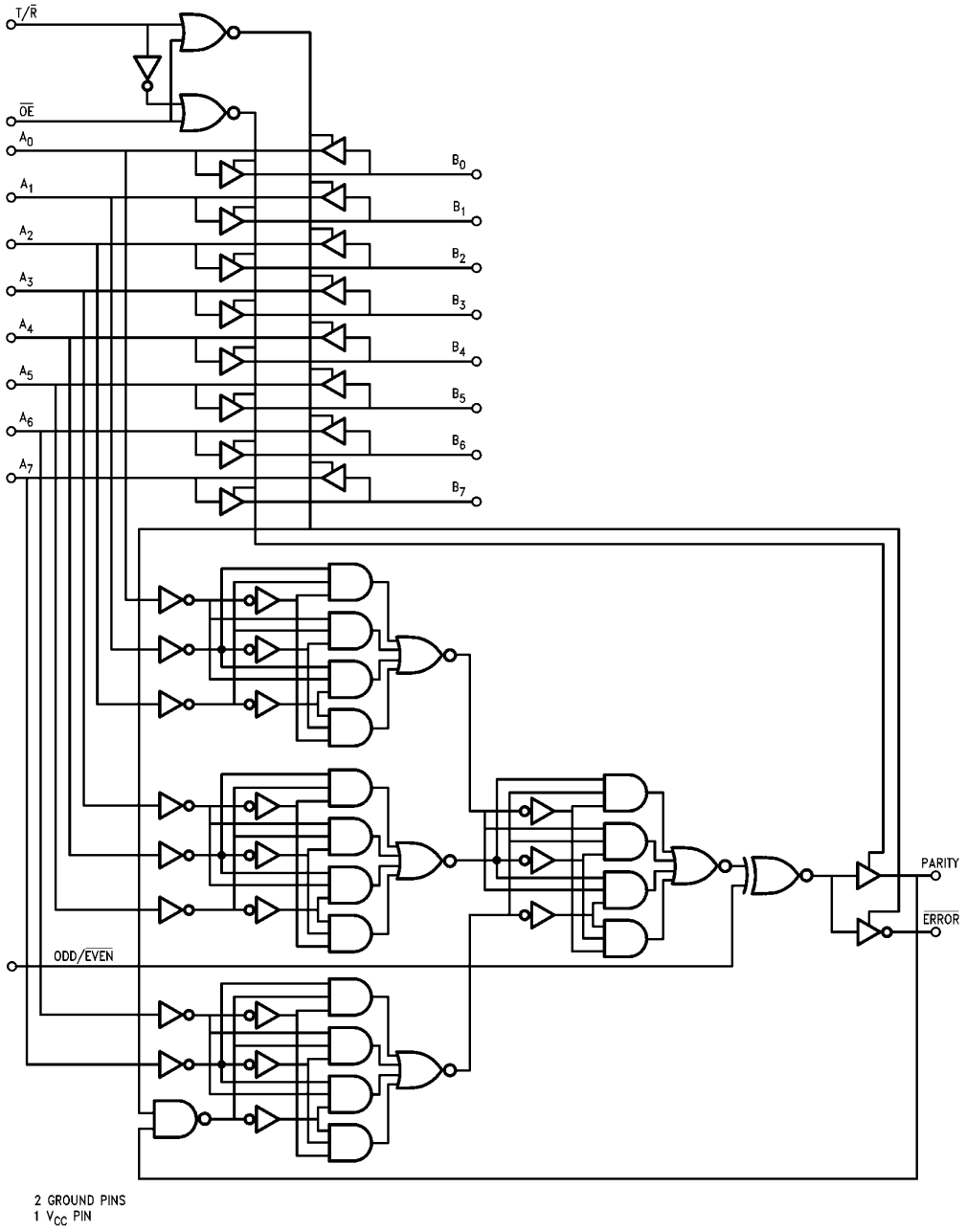
H = HIGH Voltage Level
L = LOW Voltage Level
X = Immaterial
Z = High Impedance

Function Table

Inputs		Outputs
$\overline{OE}$	$T/\overline{R}$	
L	L	Bus B Data to Bus A
L	H	Bus A Data to Bus B
H	X	High-Z State

H = HIGH Voltage Level
L = LOW Voltage Level
X = Immaterial

Functional Block Diagram



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Please note that this diagram is provided only for the understanding of logic operations and should not be used to estimate propagation delays.

Absolute Maximum Ratings (Note 1)

If Military/Aerospace specified devices are required, please contact the National Semiconductor Sales Office/Distributors for availability and specifications.

Supply Voltage (V_{CC})	−0.5V to +7.0V
DC Input Diode Current (I_{IK})	
V_I = −0.5V	−20 MA
V_I = V_{CC} + 0.5V	+20 mA
DC Input Voltage (V_I)	−0.5V to V_{CC} + 0.5V
DC Output Diode Current (I_{OK})	
V_O = −0.5V	−20 mA
V_O = V_{CC} + 0.5V	+20 mA
DC Output Voltage (V_O)	−0.5V to V_{CC} + 0.5V
DC Output Source or Sink Current (I_O)	±50 mA
DC V_{CC} or Ground Current per Output Pin (I_{CC} or I_{GND})	±50 mA
Storage Temperature (T_{STG})	−65°C to +150°C
DC Latch-up Source or Sink Current	±300 mA
Junction Temperature (T_J)	
CDIP	175°C
PDIP	140°C

Note 1: Absolute maximum ratings are those values beyond which damage to the device may occur. The databook specifications should be met, without exception, to ensure that the system design is reliable over its power supply, temperature, and output/input loading variables. National does not recommend operation of FACT circuits outside databook specifications.

Recommended Operating Conditions

Supply Voltage (V_{CC})	
'ACQ	2.0V to 6.0V
'ACTQ	4.5V to 5.5V
Input Voltage (V_I)	0V to V_{CC}
Output Voltage (V_O)	0V to V_{CC}
Operating Temperature (T_A) (Note 2)	
74ACQ/ACTQ	−40°C to +85°C
54ACTQ	−55°C to +125°C
Minimum Input Edge Rate ΔV/Δt 'ACQ Devices V_{IN} from 30% to 70% of V_{CC} V_{CC} @ 3.0V, 4.5V, 5.5V	125 mV/ns
Minimum Input Edge Rate ΔV/Δt 'ACTQ Devices V_{IN} from 0.8V to 2.0V V_{CC} @ 4.5V, 5.5V	125 mV/ns

Note 2: All commercial packaging is not recommended for applications requiring greater than 200 temperature cycles from −65°C to +150°C.

DC Characteristics for 'ACQ Family Devices

Symbol	Parameter	V_{CC} (V)	74ACQ T_A = +25°C		74ACQ T_A = −40°C to +85°C	Units	Conditions
			Typ	Guaranteed Limits			
V_{IH}	Minimum High Level Input Voltage	3.0	1.5	2.1	2.1	V	V_{OUT} = 0.1V or V_{CC} − 0.1V
		4.5	2.25	3.15	3.15		
		5.5	2.75	3.85	3.85		
V_{IL}	Maximum Low Level Input Voltage	3.0	1.5	0.9	0.9	V	V_{OUT} = 0.1V or V_{CC} − 0.1V
		4.5	2.25	1.35	1.35		
		5.5	2.75	1.65	1.65		
V_{OH}	Minimum High Level Output Voltage	3.0	2.99	2.9	2.9	V	I_{OUT} = −50 μA
		4.5	4.49	4.4	4.4		
		5.5	5.49	5.4	5.4		
		3.0		2.56	2.46	V	*V_{IN} = V_{IL} or V_{IH} I_{OH} −12 mA
		4.5		3.86	3.76		I_{OH} −24 mA
		5.5		4.85	4.76		−24 mA

*Maximum of 8 outputs loaded; thresholds on input associated with output under test.

DC Characteristics for 'ACQ Family Devices (Continued)

Symbol	Parameter	V_{CC} (V)	74ACQ		74ACQ	Units	Conditions
			$T_A = +25°C$		$T_A = -40°C$ to $+85°C$		
			Typ	Guaranteed Limits			
V_{OL}	Maximum Low Level Output Voltage	3.0	0.002	0.1	0.1	V	$I_{OUT} = 50\ \mu A$
		4.5	0.001	0.1	0.1		
		5.5	0.001	0.1	0.1		
							*$V_{IN} = V_{IL}$ or V_{IH}
		3.0		0.36	0.44	V	I_{OL} 12 mA
		4.5		0.36	0.44		I_{OL} 24 mA
		5.5		0.36	0.44		I_{OL} 24 mA
I_{IN}	Maximum Input Leakage Current ($T/\overline{R}$, $\overline{OE}$, ODD/$\overline{EVEN}$ Inputs)	5.5		± 0.1	± 1.0	μA	$V_I = V_{CC}$, GND (Note 1)
I_{OLD}	†Minimum Dynamic Output Current	5.5			75	mA	$V_{OLD} = 1.65V$ Max
I_{OHD}		5.5			-75	mA	$V_{OHD} = 3.85V$ Min
I_{CC}	Maximum Quiescent Supply Current	5.5		8.0	80.0	μA	$V_{IN} = V_{CC}$ or GND (Note 1)
I_{OZT}	Maximum I/O Leakage Current (A_n, B_n Inputs)	5.5		± 0.6	± 6.0	μA	$V_I(OE) = V_{IL}$, V_{IH} $V_I = V_{CC}$, GND $V_O = V_{CC}$, GND
V_{OLP}	Quiet Output Maximum Dynamic V_{OL}	5.0	1.1	1.5		V	*Figures 2-12*, *13* (Notes 2, 3)
V_{OLV}	Quiet Output Minimum Dynamic V_{OL}	5.0	-0.6	-1.2		V	*Figures 2-12*, *13* (Notes 2, 3)
V_{IHD}	Minimum High Level Dynamic Input Voltage	5.0	3.1	3.5		V	(Notes 2, 4)
V_{ILD}	Maximum Low Level Dynamic Input Voltage	5.0	1.9	1.5		V	(Notes 2, 4)

*Maximum of 8 outputs loaded; thresholds on input associated with output under test.

†Maximum test duration 2.0 ms, one output loaded at a time.

Note 1: I_{IN} and I_{CC} @ 3.0V are guaranteed to be less than or equal to the respective limit @ 5.5V V_{CC}.

Note 2: Plastic DIP package.

Note 3: Max number of outputs defined as (n). Data Inputs are driven 0V to 5V. One output @ GND.

Note 4: Max number of Data Inputs (n) switching. (n−1) Inputs switching 0V to 5V ('ACQ). Input-under-test switching: 5V to threshold (V_{ILD}), 0V to threshold (V_{IHD}) f = 1 MHz.

DC Characteristics for 'ACTQ Family Devices

Symbol	Parameter	V_{CC} (V)	74ACTQ $T_A = +25°C$	74ACTQ	54ACTQ $T_A = -55°C$ to $+125°C$	74ACTQ $T_A = -40°C$ to $+85°C$	Units	Conditions
			Typ	Guaranteed Limits				
V_{IH}	Minimum High Level Input Voltage	4.5 5.5	1.5 1.5	2.0 2.0	2.0 2.0	2.0 2.0	V	$V_{OUT} = 0.1V$ or $V_{CC} - 0.1V$
V_{IL}	Maximum Low Level Input Voltage	4.5 5.5	1.5 1.5	0.8 0.8	0.8 0.8	0.8 0.8	V	$V_{OUT} = 0.1V$ or $V_{CC} - 0.1V$
V_{OH}	Minimum High Level Output Voltage	4.5 5.5	4.49 5.49	4.4 5.4	4.4 5.4	4.4 5.4	V	$I_{OUT} = -50\ \mu A$
		4.5 5.5		3.86 4.86	3.70 4.70	3.76 4.76	V	*$V_{IN} = V_{IL}$ or V_{IH} I_{OH} -24 mA I_{OH} -24 mA
V_{OL}	Maximum Low Level Output Voltage	4.5 5.5	0.001 0.001	0.1 0.1	0.1 0.1	0.1 0.1	V	$I_{OUT} = 50\ \mu A$
		4.5 5.5		0.36 0.36	0.50 0.50	0.44 0.44	V	*$V_{IN} = V_{IL}$ or V_{IH} I_{OL} 24 mA I_{OL} 24 mA
I_{IN}	Maximum Input Leakage Current ($T/\overline{R}$, $\overline{OE}$, ODD/$\overline{EVEN}$ Inputs)	5.5		± 0.1	± 1.0	± 1.0	μA	$V_I = V_{CC}$, GND
I_{OZT}	Maximum I/O Leakage Current (A_n, B_n Inputs)	5.5		± 0.6	± 11.0	± 6.0	μA	$V_I = V_{IL}$, V_{IH} $V_O = V_{CC}$, GND
I_{CCT}	Maximum I_{CC}/Input	5.5	0.6		1.6	1.5	mA	$V_I = V_{CC} - 2.1V$
I_{OLD}	†Minimum Dynamic Output Current	5.5			50	75	mA	$V_{OLD} = 1.65V$ Max
I_{OHD}		5.5			-50	-75	mA	$V_{OHD} = 3.85V$ Min
I_{CC}	Maximum Quiescent Supply Current	5.5		8.0	160.0	80.0	μA	$V_{IN} = V_{CC}$ or GND (Note 1)
V_{OLP}	Quiet Output Maximum Dynamic V_{OL}	5.0	1.1	1.5			V	*Figures 2-12, 13* (Notes 2, 3)
V_{OLV}	Quiet Output Minimum Dynamic V_{OL}	5.0	-0.6	-1.2			V	*Figures 2-12, 13* (Notes 2, 3)
V_{IHD}	Minimum High Level Dynamic Input Voltage	5.0	1.9	2.2			V	(Notes 2, 4)
V_{ILD}	Maximum Low Level Dynamic Input Voltage	5.0	1.2	0.8			V	(Notes 2, 4)

*All outputs loaded; thresholds on input associated with output under test.

†Maximum test duration 2.0 ms, one output loaded at a time.

Note 1: I_{CC} for 54ACTQ @ 25°C is identical to 74ACTQ @ 25°C.

Note 2: Plastic DIP package.

Note 3: Max number of outputs defined as (n). n−1 Data Inputs are driven 0V to 3V; one output @ GND.

Note 4: Max number of Data Inputs (n) switching. (n−1) Inputs switching 0V to 3V ('ACQ). Input-under-test switching; 3V to threshold (V_{ILD}), 0V to threshold (V_{IHD}) f = 1 MHz.

AC Electrical Characteristics

Symbol	Parameter	V_{CC}* (V)	74ACQ $T_A = 25°C$, $C_L = 50$ pF			74ACQ $T_A = -40°C$ to $+85°C$, $C_L = 50$ pF		Units
			Min	Typ	Max	Min	Max	
t_{PLH}, t_{PHL}	Propagation Delay A_n to B_n, B_n to A_n	3.3	2.5	8.0	11.5	2.5	12.0	ns
		5.0	1.5	5.0	7.5	1.5	8.0	
t_{PLH}, t_{PHL}	Propagation Delay A_n to Parity	3.3	3.0	11.5	16.5	3.0	17.0	ns
		5.0	2.0	7.0	10.5	2.0	11.0	
t_{PLH}, t_{PHL}	Propagation Delay ODD/$\overline{\text{EVEN}}$ to PARITY	3.3	3.0	10.0	15.0	3.0	15.5	ns
		5.0	2.5	6.5	10.0	2.5	10.5	
t_{PLH}, t_{PHL}	Propagation Delay ODD/$\overline{\text{EVEN}}$ to $\overline{\text{ERROR}}$	3.3	3.0	10.0	15.0	3.0	15.5	ns
		5.0	2.5	6.5	10.0	2.5	10.5	
t_{PLH}, t_{PHL}	Propagation Delay B_n to $\overline{\text{ERROR}}$	3.3	3.5	11.5	16.0	3.5	16.5	ns
		5.0	2.5	7.0	10.5	2.5	11.0	
t_{PLH}, t_{PHL}	Propagation Delay PARITY to $\overline{\text{ERROR}}$	3.3	3.0	9.0	13.5	3.0	14.0	ns
		5.0	2.0	6.0	9.0	2.0	9.5	
t_{PZH}, t_{PZL}	Output Enable Time $\overline{OE}$ to A_n/B_n	3.3	2.5	9.0	13.5	2.5	14.0	ns
		5.0	2.0	6.0	9.0	2.0	9.5	
t_{PHZ}, t_{PLZ}	Output Disable Time $\overline{OE}$ to A_n/B_n	3.3	1.0	8.5	13.0	1.0	13.5	ns
		5.0	1.0	5.5	8.5	1.0	9.0	
t_{PZH}, t_{PZL}	Output Enable Time $\overline{OE}$ to $\overline{\text{ERROR}}$ (Note 1)	3.3	2.5	9.0	13.5	2.5	14.0	ns
		5.0	2.0	6.0	9.0	2.0	9.5	
t_{PHZ}, t_{PLZ}	Output Disable Time $\overline{OE}$ to $\overline{\text{ERROR}}$	3.3	1.0	8.5	13.0	1.0	13.5	ns
		5.0	1.0	5.5	8.5	1.0	9.0	
t_{PZH}, t_{PZL}	Output Enable Time $\overline{OE}$ to PARITY	3.3	2.5	9.0	13.5	2.5	14.0	ns
		5.0	2.0	6.0	9.0	2.0	9.5	
t_{PHZ}, t_{PLZ}	Output Disable Time $\overline{OE}$ to PARITY	3.3	1.0	8.5	13.0	1.0	13.5	ns
		5.0	1.0	5.5	8.5	1.0	9.0	
t_{OSHL}, t_{OSLH}	Output to Output Skew** A_n, B_n to B_n, A_n	3.3		1.0	1.5		1.5	ns
		5.0		0.5	1.0		1.0	

*Voltage Range 3.3 is 3.3V ±0.3V

Voltage Range 5.0 is 5.0V ±0.5V

**Skew is defined as the absolute value of the difference between the actual propagation delay for any two outputs within the same packaged device. The specification applies to any outputs switching in the same direction, either HIGH to LOW (t_{OSHL}) or LOW to HIGH (t_{OSLH}). Parameter guaranteed by design. Not tested.

Note 1: These delay times reflect the TRI-STATE recovery time only and not the signal time through the buffers or the parity check circuitry. To assure VALID information at the $\overline{\text{ERROR}}$ pin, time must be allowed for the signal to propagate through the drivers (B to A), through the parity check circuitry (same as A to PARITY), and to the $\overline{\text{ERROR}}$ output after the $\overline{\text{ERROR}}$ pin has been enabled (Output Enable times). VALID data at the $\overline{\text{ERROR}}$ pin $\geq$ (A to PARITY) + (Output Enable Time).

AC Electrical Characteristics

Symbol	Parameter	V_{CC}* (V)	74ACTQ $T_A = 25°C$, $C_L = 50$ pF			54ACTQ $T_A = -55°C$ to $+125°C$, $C_L = 50$ pF		74ACTQ $T_A = -40°C$ to $+85°C$, $C_L = 50$ pF		Units
			Min	Typ	Max	Min	Max	Min	Max	
t_{PLH}, t_{PHL}	Propagation Delay A_n to B_n, B_n to A_n	5.0	1.5	5.0	8.0	1.5	9.0	1.5	8.5	ns
t_{PLH}, t_{PHL}	Propagation Delay A_n to Parity	5.0	2.5	7.5	11.0	1.5	13.5	2.5	11.5	ns
t_{PLH}, t_{PHL}	Propagation Delay ODD/$\overline{\text{EVEN}}$ to PARITY	5.0	2.5	6.5	10.5	1.5	10.5	2.5	11.0	ns
t_{PLH}, t_{PHL}	Propagation Delay ODD/$\overline{\text{EVEN}}$ to $\overline{\text{ERROR}}$	5.0	2.5	6.5	10.5	1.5	11.0	2.5	11.0	ns
t_{PLH}, t_{PHL}	Propagation Delay B_n to $\overline{\text{ERROR}}$	5.0	3.0	7.5	11.0	1.5	13.5	3.0	11.5	ns
t_{PLH}, t_{PHL}	Propagation Delay PARITY to $\overline{\text{ERROR}}$	5.0	2.0	6.0	9.5	1.5	10.5	2.0	10.0	ns
t_{PZH}, t_{PZL}	Output Enable Time $\overline{OE}$ to A_n/B_n	5.0	2.0	6.0	9.5	1.5	12.0	2.0	10.0	ns
t_{PHZ}, t_{PLZ}	Output Disable Time $\overline{OE}$ to A_n/B_n	5.0	1.0	5.0	9.0	1.5	9.0	1.0	9.5	ns
t_{PZH}, t_{PZL}	Output Enable Time $\overline{OE}$ to $\overline{\text{ERROR}}$ (Note 1)	5.0	2.0	6.0	9.5	1.5	11.5	2.0	10.0	ns
t_{PHZ}, t_{PLZ}	Output Disable Time $\overline{OE}$ to $\overline{\text{ERROR}}$	5.0	1.0	6.0	9.0	1.5	9.0	1.0	9.5	ns
t_{PZH}, t_{PZL}	Output Enable Time $\overline{OE}$ to PARITY	5.0	2.0	6.0	9.5	1.5	11.5	2.0	10.0	ns
t_{PHZ}, t_{PLZ}	Output Disable Time $\overline{OE}$ to PARITY	5.0	1.0	5.0	9.0	1.5	8.5	1.0	9.5	ns
t_{OSHL}, t_{OSLH}	Output to Output Skew** A_n, B_n to B_n, A_n	5.0		0.5	1.0				1.0	ns

*Voltage Range 5.0 is 5.0V ±0.5V

**Skew is defined as the absolute value of the difference between the actual propagation delay for any two outputs within the same packaged device. The specification applies to any outputs switching in the same direction, either HIGH to LOW (t_{OSHL}) or LOW to HIGH (t_{OSLH}). Parameter guaranteed by design. Not tested.

Note 1: These delay times reflect the TRI-STATE recovery time only and not the signal time through the buffers or the parity check circuitry. To assure VALID information at the $\overline{\text{ERROR}}$ pin, time must be allowed for the signal to propagate through the drivers (B to A), through the parity check circuitry (same as A to PARITY), and to the $\overline{\text{ERROR}}$ output after the $\overline{\text{ERROR}}$ pin has been enabled (Output Enable times). VALID data at the $\overline{\text{ERROR}}$ pin $\geq$ (A to PARITY) + (Output Enable Time).

Capacitance

Symbol	Parameter	Typ	Units	Conditions
C_{IN}	Input Capacitance	4.5	pF	$V_{CC} = 5.0V$
C_{PD}	Power Dissipation Capacitance	160.0	pF	$V_{CC} = 5.0V$

FACT Noise Characteristics

The setup of a noise characteristics measurement is critical to the accuracy and repeatability of the tests. The following is a brief description of the setup used to measure the noise characteristics of FACT.

Equipment:

Hewlett Packard Model 8180A Word Generator
PC-163A Test Fixture
Tektronics Model 7854 Oscilloscope

Procedure:

1. Verify Test Fixture Loading: Standard Load 50 pF, 500Ω.
2. Deskew the word generator so that no two channels have greater than 150 ps skew between them. This requires that the oscilloscope be deskewed first. Swap out the channels that have more than 150 ps of skew until all channels being used are within 150 ps. It is important to deskew the word generator channels before testing. This will ensure that the outputs switch simultaneously.
3. Terminate all inputs and outputs to ensure proper loading of the outputs and that the input levels are at the correct voltage.

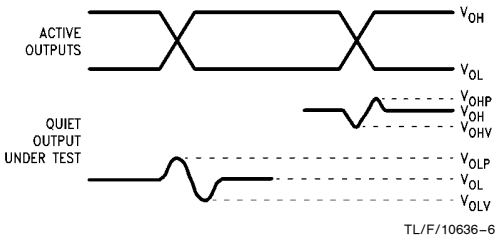

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FIGURE 1. Quiet Output Noise Voltage Waveforms

Note A. V_{OHV} and V_{OLP} are measured with respect to ground reference.

Note B. Input pulses have the following characteristics: f = 1 MHz, t_r = 3 ns, t_f = 3 ns, skew < 150 ps.

4. Set V_{CC} to 5.0V.
5. Set the word generator to toggle all but one output at a frequency of 1 MHz. Greater frequencies will increase DUT heating and affect the results of the measurement.
6. Set the word generator input levels at 0V LOW and 3V HIGH for ACT devices and 0V LOW and 5V HIGH for AC devices. Verify levels with a digital volt meter.

V_{OLP}/V_{OLV} and V_{OHP}/V_{OHV}:

- Determine the quiet output pin that demonstrates the greatest noise levels. The worst case pin will usually be the furthest from the ground pin. Monitor the output voltages using a 50Ω coaxial cable plugged into a standard SMB type connector on the test fixture. Do not use an active FET probe.
- Measure V_{OLP} and V_{OLV} on the quiet output during the HL transition. Measure V_{OHP} and V_{OHV} on the quiet output during the LH transition.
- Verify that the GND reference recorded on the oscilloscope has not drifted to ensure the accuracy and repeatability of the measurements.

V_{ILD} and V_{IHD}:

- Monitor one of the switching outputs using a 50Ω coaxial cable plugged into a standard SMB type connector on the test fixture. Do not use an active FET probe.
- First increase the input LOW voltage level, V_{IL}, until the output begins to oscillate. Oscillation is defined as noise on the output LOW level that exceeds V_{IL} limits, or on output HIGH levels that exceed V_{IH} limits. The input LOW voltage level at which oscillation occurs is defined as V_{ILD}.
- Next increase the input HIGH voltage level on the word generator, V_{IH} until the output begins to oscillate. Oscillation is defined as noise on the output LOW level that exceeds V_{IL} limits, or on output HIGH levels that exceed V_{IH} limits. The input HIGH voltage level at which oscillation occurs is defined as V_{IHD}.
- Verify that the GND reference recorded on the oscilloscope has not drifted to ensure the accuracy and repeatability of the measurements.

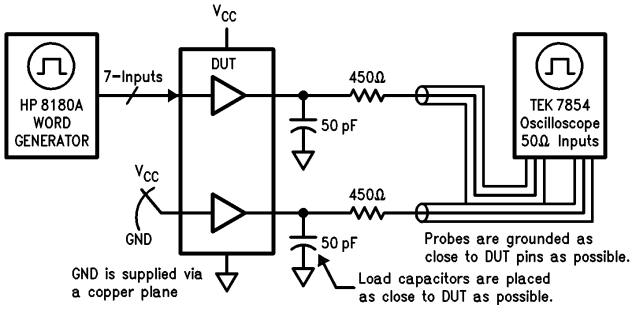

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FIGURE 2. Simultaneous Switching Test Circuit

Ordering Information

The device number is used to form part of a simplified purchasing code where the package type and temperature range are defined as follows:

74ACTQ 657 P C QR

Temperature Range Family
- 74ACQ = Commercial
- 74ACTQ = Commercial TTL-Compatible
- 54ACTQ = Military TTL-Compatible

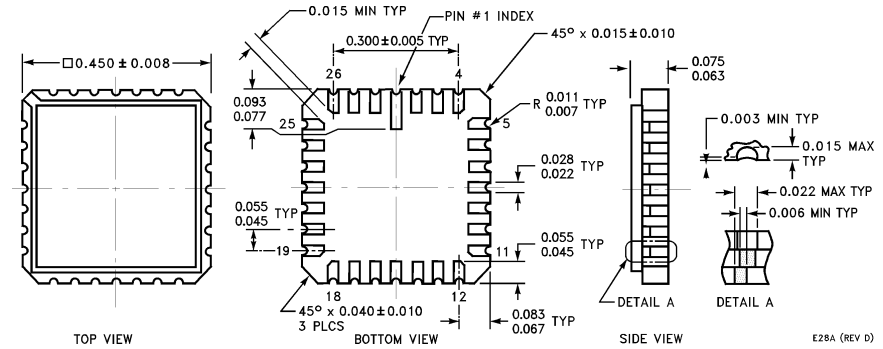
Device Type

Package Code
- SP = Slim Plastic DIP
- SD = Slim Ceramic DIP
- F = Flatpak
- L = Leadless Ceramic Chip Carrier (LCC)

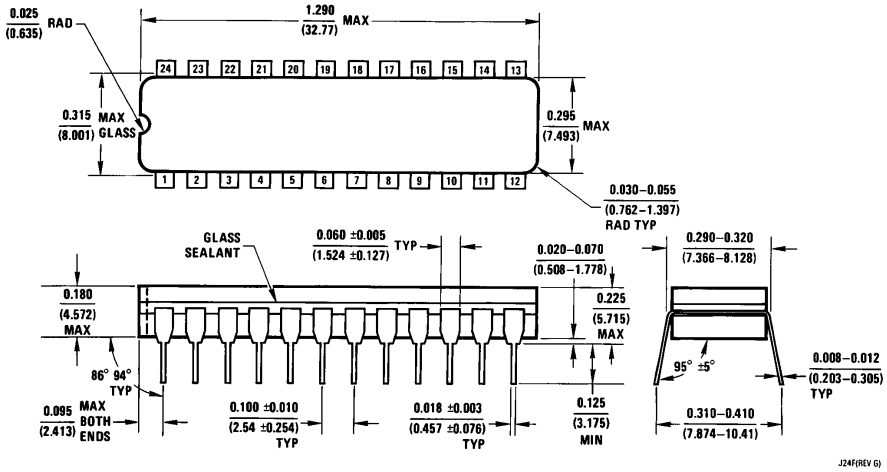
Temperature Range
- C = Commercial (−40°C to +85°C)
- M = Military (−55°C to +125°C)

Special Variations
- X = Device shipped in 13″ reels
- QR = Commercial grade device with burn-in
- QB = Military grade device with environmental and burn-in processing shipped in tubes

Physical Dimensions inches (millimeters)

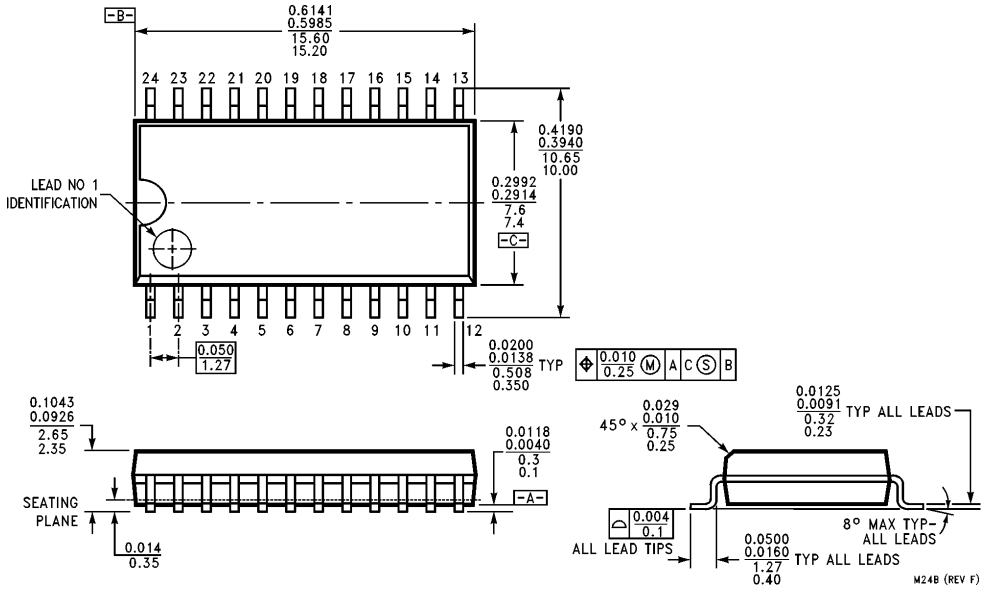


28-Terminal Ceramic Leadless Chip Carrier (L)
NS Package Number E28A

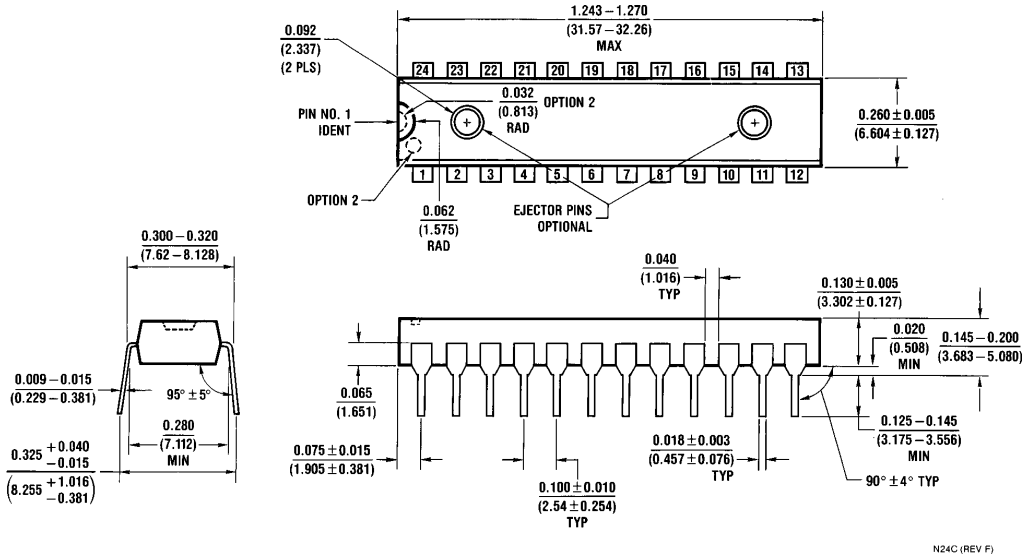


24-Lead Slim Ceramic (0.300″ Wide)
Dual-In-Line Package (SD)
NS Package Number J24F

Physical Dimensions inches (millimeters) (Continued)



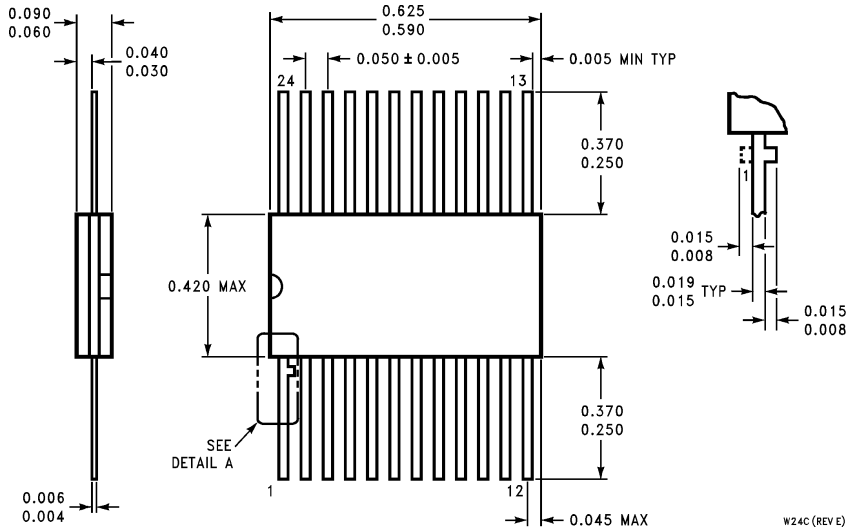
24-Lead Small Outline Integrated Circuit (S)
NS Package Number M24B



24-Lead Slim Plastic (0.300″ Wide)
Dual-In-Line Package (SP)
NS Package Number N24C

Physical Dimensions inches (millimeters) (Continued)

Lit. # 115120



24-Lead Ceramic Flatpak (F)
NS Package Number W24C

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2. A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

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